

10/23/2014



**RELIABILITY MONITOR REPORT  
FOR**

**X3 0.4µm Silicon Gate (S4)**

**MAXIM INTEGRATED**

**160 RIO ROBLES  
SAN JOSE, CA 95134**

**This Report was prepared by  
MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX24101ELU+

The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 7654 QUANTITY: 79 FAILS: 0 FITS: 14.9**

The parameters used to calculate this failure rate are as follows:

**Cf: 60% Ea: 0.7 Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2013 and 9/30/2014 .

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**Process Information:**

Process Description: X3 0.4µm Silicon Gate (S4)

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1325	MAX24101ELU+	135°C	500 HRS	79	0	KAK1AQ3A
<b>Total:</b>						<b>0</b>	
<b>FAILURE RATE:</b>	<b>MTTF (YRS): 7654</b>		<b>QUANTITY: 79</b>	<b>FAILS: 0</b>	<b>FITS: 14.9</b>		